

## Special Issue

# Advanced Dental Imaging Technology

### Message from the Guest Editors

This issue focuses on the comprehensive exploration of advanced dental imaging technology, encompassing its development, implementation, and impact on modern dentistry. Advanced dental imaging technologies are based on cutting-edge systems that combine structural accuracy with functional diagnostics. One of the most significant advancements is cone-beam computed tomography (CBCT), which provides high-resolution 3D images of dental structures. Additionally, digital radiography has revolutionized traditional X-ray techniques, offering enhanced image quality and reduced radiation exposure. The integration of artificial intelligence in dental imaging has broadened the possibilities for automated diagnosis, treatment planning, and image analysis. These technologies are being rapidly adopted across various dental specialties, addressing critical needs in areas such as orthodontics, endodontics, and oral surgery. The continuous evolution of these imaging modalities promises to improve diagnostic accuracy, treatment outcomes, and patient care, ultimately contributing to the advancement of dental health and education.

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### Deadline for manuscript submissions

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### Editor-in-Chief

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